

1. Record Nr.	UNISA996218755803316
Titolo	VLSI Test Symposium (VTS 2000): 18th IEEE
Pubbl/distr/stampa	[Place of publication not identified], : IEEE Computer Society Press, 2000
Descrizione fisica	1 online resource (478 pages) : illustrations
Disciplina	621.3950287
Soggetti	Integrated circuits - Very large scale integration - Testing
Lingua di pubblicazione	Inglese
Formato	Materiale a stampa
Livello bibliografico	Monografia
Note generali	Bibliographic Level Mode of Issuance: Monograph
Nota di bibliografia	Includes bibliographical references and index.
Nota di contenuto	Foreword -- Organizing Committee -- Steering Committe -- Program Committee -- Reviewers -- VTS '99 Best Paper Award -- VTS '99 Best Panel Award -- Test Technology Technical Council -- Test Technology Education Program: Overview Tutorials -- Plenary Session -- Welcome Message -- Adit Singh -- Keynote Address: "Optical Internet: Industry Challenge" -- Brian McFadden -- Program Introduction -- Joan Figueras -- Invited Presentation: "Wall Street Perspective on System-on-Chip and Test Technology" -- Erach D. Desai.
Sommario/riassunto	Proceedings of a spring 2000 symposium, highlighting novel ideas and approaches to current and future problems related to testing of electronic circuits and systems. Themes are microprocessor test/validation, low power BIST and scan, technology trends, scan-related approaches, defect-driven techniques, and system-on-chip test techniques. Other subjects are analog test techniques, temperature and process drift issues, test compaction and design validation, analog BIST, and functional test and verification issues. Also covered are STIL extension, IDDQ test, and on-line testing and fault tolerance. Lacks a subject index. Annotation copyrighted by Book News, Inc., Portland, OR.